Notice of References Cited

Application/Control No.

09/894,260

Examiner

Amol V. Gole

Applicant(s)/Patent Under
Reeyamination
EICKEMEYER ET AL.

Art Unit
Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	Α	US-6,629,271 B1	09-2003	Lee et al.	714/49
	В	US-2002/0078317 A1	06-2002	Yasoshima, Hiroyuki	711/171
	С	US-6,311,261 B1	10-2001	Chamdani et al.	712/23
	D	US-5,623,608 A	04-1997	Ng, Spencer WF.	711/137
	Ε	US-2001/0032307 A1	10-2001	ROHLMAN et al.	717/37
	F	US-6,507,921 B1	01-2003	Buser et al.	714/45
	G	US-6,075,931 A	06-2000	Panwar, Ramesh	
	н	US-2003/0105944 A1	06-2003	Emer et al.	716/1
	ı	US-5,465,120 A	11-1995	Schultheiss, John C.	712/220
	J	US-2003/0061258 A1	03-2003	Rodgers et al.	348/716
	к	US-			709/102
1	L	US-			
7	М	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
ł	N					
Г	0					
	Р					
	Q					
	R					
-	s					
	Т					
لــــا						

NON-PATENT DOCUMENTS

*	1	Include as applicable. Author Title Date Date:		
 	\dagger	Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)		
	U	Gulati, M., Bagherzadeh, N. "Performance Study of a Multithreaded Superscalar Microprocessor". Proc. of the 2 nd International Symposium on High-Performance Computer Architectures, February 1996, 291-301		
	v	Ponomarev, D., Kucuk, G., Ghose, K., "Dynamic Allocation of Datapath Resources for Low Power", in Proc. of Workshop on Complexity-Effective Design, held in conjunction with ISCA-28, June 2001		
	w	Daniele Folegnani , Antonio González, "Energy-effective issue logic", Proceedings of the 28th annual international symposium on Computer architecture, p.230-239, June 30-July 04, 2001, Göteborg, Sweden		
 - 	×	S. Reinhardt and S. Mukherjee, "Transient fault detection via simultaneous multithreading" 27th Int'l Symp. on Computer Architecture, June 2000		

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.